

# Partial oxidation of CH<sub>4</sub> at low pressure over SiO<sub>2</sub> prepared from Si

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The oxidation of CH<sub>4</sub> with O<sub>2</sub> at low pressure was carried out over SiO<sub>2</sub> prepared from metal Si. The Si showed only total oxidation activity while the Si partly oxidized to SiO<sub>2</sub> showed high selectivities to CH<sub>3</sub>OH and HCHO. The results on SiO<sub>2</sub> prepared from Si were compared with those over commercial silicas. The role of SiO<sub>2</sub> in the CH<sub>4</sub> oxidation was discussed.

**Keywords:** partial oxidation of CH<sub>4</sub>; CH<sub>3</sub>OH; HCHO; SiO<sub>2</sub> catalyst

## 1. Introduction

The conversion of CH<sub>4</sub> to CH<sub>3</sub>OH and HCHO has been studied by many workers [1–3]. The direct oxidation of CH<sub>4</sub> into CH<sub>3</sub>OH at high pressures using glass coated reactors or Pyrex and quartz reactors have been reported by some workers [4,5]. The CH<sub>3</sub>OH and HCHO formation from CH<sub>4</sub> has been studied over Mo- or V-oxide/SiO<sub>2</sub> catalysts using N<sub>2</sub>O as an oxidant [6–8]. The HCHO formation has been studied over Fe-, V-, and Mo-oxide/SiO<sub>2</sub> [9–11] using O<sub>2</sub> as an oxidant. It is interesting that the selective partial oxidation in these reports occurs over “silica”-based catalysts. Some workers have focused their attention on SiO<sub>2</sub> itself [12–14].

Previously, we also studied [15] the CH<sub>3</sub>OH and HCHO formations in the oxidation of CH<sub>4</sub> using O<sub>2</sub> over various commercial SiO<sub>2</sub> catalysts. In this work, we tried to measure the oxidation rates under special conditions over SiO<sub>2</sub> catalyst prepared from metal Si in order to obtain the initial rate of partial oxidation and to understand the role of SiO<sub>2</sub> itself basically. The results were compared with those over various commercial silicas. The effects of oxygen pressures, surface area, and impurities in SiO<sub>2</sub> were examined. The percent of <sup>18</sup>O in the products was also examined using <sup>18</sup>O<sub>2</sub> as a reactant. The heterogeneous and homogeneous processes in the partial oxidation were also discussed.

## 2. Methods

### 2.1. Materials

SiO<sub>2</sub> was obtained by heating the Si metal (Nakarai Tesque Co., 99.99%) in air at 1173–1373 K. The amount of SiO<sub>2</sub> (mol% in the Si sample) was calculated from the weight increase after heating in the furnace. Commercial silicas such as ADM (Shin-Etutsu Chemicals Co.), Silica

gel-60-extra pure (Merck Co.), SIO-4 (JRC, Catalysis Society of Japan), and Aerosil-300 and OX-50 (Nippon Aerosil Co.) were used. CH<sub>4</sub> (> 99%), O<sub>2</sub> (> 99%), and <sup>18</sup>O<sub>2</sub> (98.1 at%, Isotec Inc.) were used as reactants.

### 2.2. Procedures

CH<sub>4</sub> oxidations were carried out using a closed circulation system (ca. 300 cm<sup>3</sup>) made of Pyrex glass and a reactor made of quartz (fig. 1). Reactant mixtures of ca. 8 Torr of CH<sub>4</sub> and 0.08–0.24 Torr of O<sub>2</sub> were used for the reaction experiments. The circulation time was regarded as reaction time for 1 or 2 h. Products such as CH<sub>3</sub>OH, HCHO, CO<sub>2</sub>, and H<sub>2</sub>O were caught by a trap at 77 K (fig. 1) during the reaction at 873–973 K. The quartz reactor itself has a slight activity but it was very small, below ca. 5% of the catalytic activity at 873 K. The formation of CO is negligibly small in this case. A

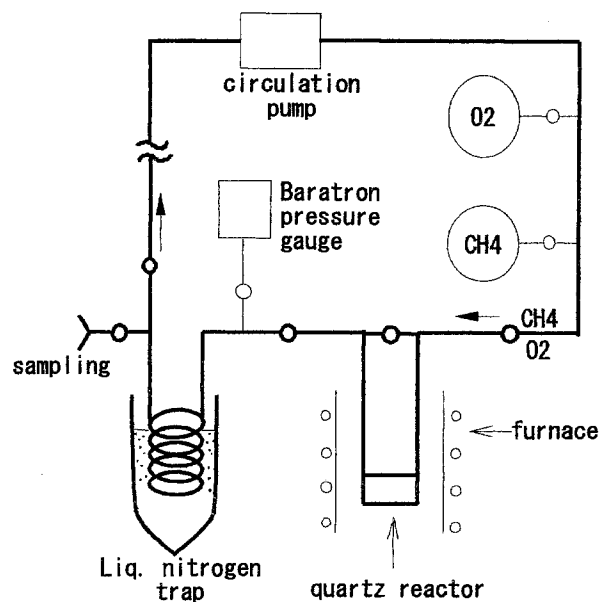


Fig. 1. A closed circulation system for CH<sub>4</sub> partial oxidation.

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short pass was set between the reactor and trap to prevent polymerization of HCHO. After the reaction, the products such as CH<sub>3</sub>OH, HCHO, H<sub>2</sub>O and CO<sub>2</sub> were kept in the sample tubes at 77 K to prevent HCHO polymerization. Their amounts were determined by gas chromatography using a TSR-1 column. In order to separate water and HCHO well, the pass in front of the column was preheated at ca. 393 K.

In this experiment, an initial rate of CH<sub>4</sub> oxidation is always obtained since only reactants such as CH<sub>4</sub> and O<sub>2</sub> are circulating and their pressures do not decrease so much since the CH<sub>4</sub> and O<sub>2</sub> conversions are below 2–5% and 10–15%, respectively. The CH<sub>4</sub> pressure in this experiment is limited below the saturation pressure at 77 K, i.e., 9.7 Torr.

The <sup>18</sup>O% in the products were recorded on a Shimadzu QP-2000A mass spectrometer. The percent of <sup>18</sup>O in HCHO and in CO<sub>2</sub> was well determined while that in CH<sub>3</sub>OH was not determined owing to disturbance by a small amount of air (32: O<sub>2</sub>) in the mass spectrometer. The sample gases were introduced directly to the ion chamber without using a separating column in order to prevent the exchange with <sup>16</sup>O water in the column.

### 3. Results and discussion

#### 3.1. SiO<sub>2</sub> catalysts prepared from Si

The oxidation of Si to SiO<sub>2</sub> by air was very low when it was not ground in a mortar while it was oxidized rapidly when it was ground prior to heating. An unoxidized Si and a slightly oxidized Si(5.6%) sample showed the same diffraction patterns of metal Si (cubic system, JPDSC 27-1402) according to X-ray measurements. The FT-IR spectra of metal Si showed no IR absorption. With the 5.6% catalyst, several bands at around 1000–1250 cm<sup>-1</sup> were observed, which are the same as the results reported for the thin SiO<sub>2</sub> film [16]. These have been attributed to the longitudinal and transversal optical splittings of Si–O vibrations. With the 11–19% catalysts, the intensity of the Si–O band at around 1125 cm<sup>-1</sup> gets stronger. This suggests that SiO<sub>2</sub> crystal layers become thick for these catalysts. In the case of metal Si, however, it has been reported [17–19] that its surface is generally covered with several layers of protective oxide and that the states of Si<sup>1+–3+</sup> as well as Si<sup>4+</sup> seem to be present.

#### 3.2. Oxidation of CH<sub>4</sub> over SiO<sub>2</sub> prepared from metal Si

The partial oxidation of CH<sub>4</sub> was carried out over SiO<sub>2</sub> prepared from Si as described above. The results are shown in table 1. In this work, the CO formation was negligibly small. There is no selectivity to CH<sub>3</sub>OH and HCHO over the metal Si catalyst though CO<sub>2</sub> formation

Table 1

The activities of partial oxidation of CH<sub>4</sub> over SiO<sub>2</sub> prepared from metal Si. *p*(CH<sub>4</sub>) = 8.3 Torr (1 Torr = 133.3 Pa), concentration of O<sub>2</sub> = 3%, temperature = 873 K, catalyst: 0.5 g<sup>a</sup>

Catalyst SiO <sub>2</sub> (mol%)	CH <sub>4</sub> conversion (% g <sup>-1</sup> h <sup>-1</sup> )	Product selectivity (%)		
		CH <sub>3</sub> OH	HCHO	CO <sub>2</sub>
Si	0.2	0	0	100
Si5.6	0.63	13	40	46
Si11	0.88	3	63	33
Si19	0.94	18	64	18
Si*9.6	1 0.08	36	0	64
	2 0.10	8	23	69
Si*19	1 0.19	70	0	30
	2 0.29	37	17	46
	3 0.35	21	39	40

<sup>a</sup> The Si5.6–19 catalysts were prepared after grinding of Si. The Si\*9.6–\*19 catalysts were prepared without grinding of Si. The numbers of 1, 2, and 3 for Si\* catalysts denote the first, second, and third experiments for 1 h each. Oxygen conversions were below 10–15% in 1 h for these reactions.

occurs on it. With the Si5.6 catalyst, the selectivity to HCHO increases remarkably and the activity also increases. With the Si11 and Si19 catalysts, the selectivities to HCHO formation and the activities slightly increase. The selectivities to CH<sub>3</sub>OH over these catalysts range around 15%. These results confirm that the selectivities to partial oxidation products such as HCHO and CH<sub>3</sub>OH increase by the presence of thick SiO<sub>2</sub> crystal layers on the surface of Si. As described before, the metal Si has nanolayers of SiO<sub>2</sub> [17–19] on the surface. But, these thin layers do not have partial oxidation activity here.

The activities and selectivities for partial oxidation of CH<sub>4</sub> vary remarkably with the catalyst conditions. For example, the catalysts which were heated and prepared after grinding the metal Si in a mortar had good activities as described above. The catalysts prepared from Si without grinding had low activities for the CH<sub>4</sub> oxidation as shown also in table 1. The Si\*9.6 and \*19 catalysts show low activity but high selectivity to CH<sub>3</sub>OH in the first experiment. When the CH<sub>4</sub> oxidations are repeated for each 1 h, the activities and selectivities gradually change as shown in table 1. The selectivity to CH<sub>3</sub>OH decreases and that to HCHO increases. This suggests that the SiO<sub>2</sub> surface changes after the reactions. Fig. 2 shows these selectivities as a function of CH<sub>4</sub> conversion over many SiO<sub>2</sub> catalysts which are prepared from Si as described above. The CH<sub>3</sub>OH selectivity is higher at low conversion range below 0.2%. The selectivity to HCHO becomes higher at the conversion range above 1%. The selectivity to CO<sub>2</sub> ranges from 60 to 40%. This suggests that CH<sub>3</sub>OH is formed initially at very low conversions below ca. 0.2% and CH<sub>3</sub>OH seems to be rapidly dehydrogenated to HCHO. The total oxidation to CO<sub>2</sub> seems to occur independently for partial oxidation. Previous workers [12–

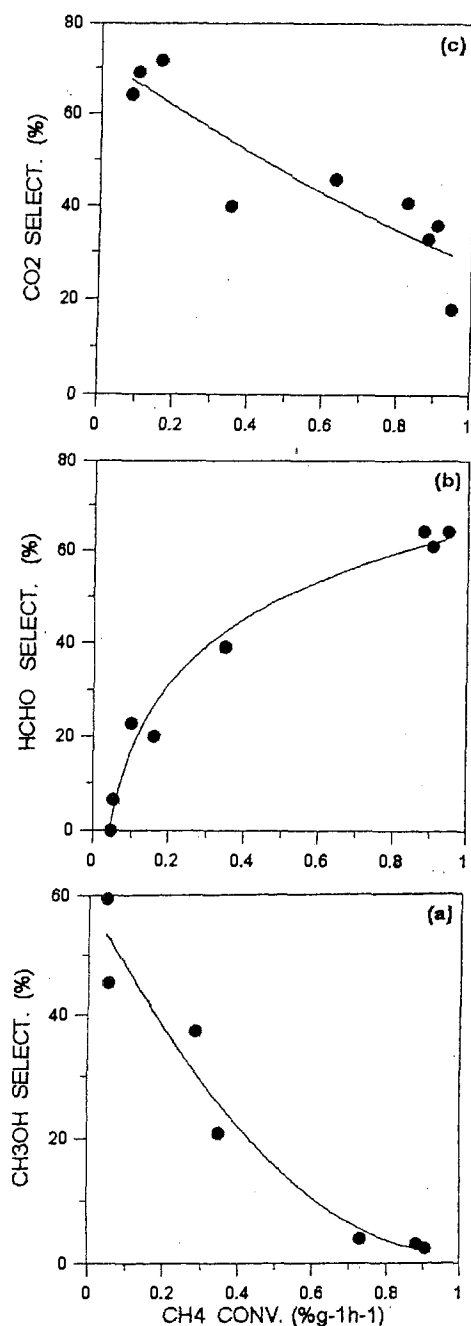


Fig. 2. The  $\text{CH}_3\text{OH}$  (a),  $\text{HCHO}$  (b), and  $\text{CO}_2$  (c) selectivities in the  $\text{CH}_4$  oxidation as a function of conversion over  $\text{SiO}_2$  prepared from metal Si.  $p(\text{CH}_4) = 8.3$  Torr, concentration of  $\text{O}_2 = \text{ca. } 3\%$ , temperature = 873 K, catalysts: Si5.6–Si29 and Si\*5–\*19 samples, 0.3–0.5 g were used.

14] have reported the formation of only  $\text{HCHO}$  in partial oxidation over  $\text{SiO}_2$ . In this work at low pressure, the  $\text{CH}_3\text{OH}$  formation was confirmed. Only  $\text{CO}_2$  formation takes place in spite of low  $\text{CH}_4$  conversion over the metal Si catalyst. As described above, its surface is covered with very thin layers of suboxides as well as  $\text{SiO}_2$ . Such a feature seems to be due to the different activities for hydrogen abstraction and  $\text{CO}_2$  formation on suboxides. Details are unclear.

### 3.3. Dependence on oxygen pressure of $\text{CH}_4$ oxidation

The rate of oxidation of  $\text{CH}_4$  was examined at some oxygen pressures (fig. 3). The ADM silica was used as a catalyst since it was prepared by heating of metal Si. The rate of conversion increases with an increase of oxygen pressures. The selectivity to  $\text{CH}_3\text{OH}$  is high below 1% of  $\text{O}_2$  concentration, while that to  $\text{HCHO}$  becomes high above 2–3% of  $\text{O}_2$ . In the absence of gaseous oxygen, the oxidation reaction does not proceed, in agreement with the results by Parmaliana et al. [13]. These results suggest that gaseous oxygen is needed for the partial oxidation of  $\text{CH}_4$ .

### 3.4. Comparison of oxidation activities between Si5.6 and various commercial silicas

The activities and selectivities of the partial oxidation of  $\text{CH}_4$  over various silicas are compared to each other. The results are shown in table 2. The rates of conversion range from 0.6 to  $1.2\% \text{ g}^{-1} \text{ h}^{-1}$ . The selectivities to  $\text{HCHO}$  range from 40 to 15%. Such differences, however, are not big among these silicas. The surface area of the Si5.6 sample is ca.  $0.5 \text{ m}^2 \text{ g}^{-1}$  while those of A300 and SIO-4 are  $300\text{--}350 \text{ m}^2 \text{ g}^{-1}$ . It is concluded that the size of surface area has essentially little effect on the oxidation rates.

Table 2 includes the impurities in the silicas. The SIO-4 contains very low impurities below several ppm. The OX50 contains 100–800 ppm of  $\text{Al}_2\text{O}_3$ ,  $\text{Fe}_2\text{O}_3$  and  $\text{TiO}_2$ . Both rates for  $\text{CH}_4$  oxidation, however, are nearly the same. The ADM silica contains 400 ppm of  $\text{Al}_2\text{O}_3$  and 275 ppm of  $\text{CaO}$ . But there is little rate difference between the Si5.6 and ADM silica catalyst. These suggest that the rates are independent of the impurities as far as their concentrations are concerned as described

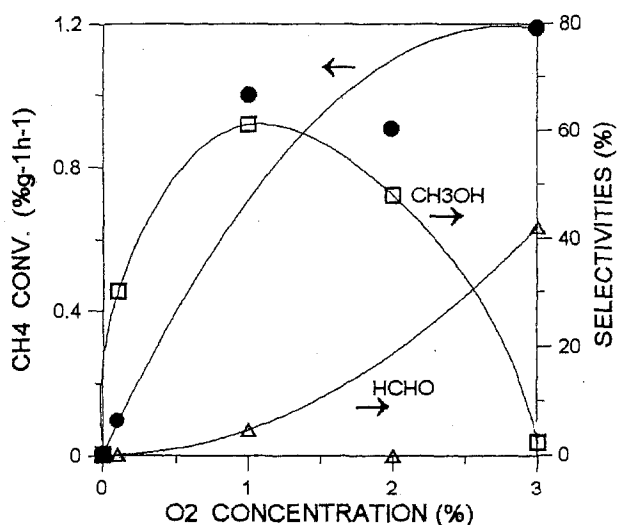


Fig. 3. The  $\text{CH}_4$  conversion and product selectivities as a function of  $\text{O}_2$  concentration.  $p(\text{CH}_4) = 8.3$  Torr, temperature = 873 K, catalyst: ADM silica 0.3 g.

Table 2

Comparison of oxidation activities and properties between Si5.6 and various commercial silicas.  $p(\text{CH}_4) = 8.3$  Torr, concentration of O<sub>2</sub> = 3%, temperature = 873 K, catalyst: 0.3–0.5 g

	Si5.6 (this work)	ADM (Shin-Etsu Chem.)	A300 (Japan Aerosil)	OX50 (Japan Aerosil)	SIO-4 (JRC) <sup>a</sup>	Silicagel 60/E.P. (Merck)
CH <sub>4</sub> conv. (% g <sup>-1</sup> h <sup>-1</sup> )	0.63	1.2	0.57	1.0	1.1	0.56
HCHO (%)	40	42	13	17	43	60
CH <sub>3</sub> OH (%)	13	4	3	6	8	16
surface area (m <sup>2</sup> g <sup>-1</sup> )	0.5	12	300	50	350	400
impurities (ppm)						
Al <sub>2</sub> O <sub>3</sub>	< 10	400	< 100	< 800	6.6	–
Fe <sub>2</sub> O <sub>3</sub>	< 25	55	< 10	< 100	0.5	< 2
TiO <sub>2</sub>	< 5	–	< 100	< 300	1.9	–
CaO	< 1	275	–	–	0.3	–

<sup>a</sup> See text. The previous results [15] over A300 and ADM silica are somewhat different from those listed here. This is caused by the circulation speed in the circulation system. Oxygen conversions were below 10–20% for these reactions in 1 h.

above. The selectivities to HCHO on A300 and OX50 are a little smaller than those on the SIO-4, ADM, and Si5.6 silicas. This seems to be caused by the presence of TiO<sub>2</sub> in the former silica, i.e., further oxidation to CO<sub>2</sub> and CO.

### 3.5. The <sup>18</sup>O tracer studies over some silica catalysts

The partial oxidation of CH<sub>4</sub> using <sup>18</sup>O<sub>2</sub> (98%) was carried out over the Si5.6 and SIO-4 catalysts. With the Si5.6 catalyst, the <sup>18</sup>O% in HCHO, H<sub>2</sub>O, and CO<sub>2</sub> which were obtained under similar conditions in table 1 (0.3% g<sup>-1</sup> of CH<sub>4</sub> conversion for 0.5 h) were 3, 0.5, and 50%, respectively. With the SIO-4 catalyst, those of HCHO, H<sub>2</sub>O, and CO<sub>2</sub> were 2, 1, and 20%, respectively, under the same conditions in table 2 (2.1% g<sup>-1</sup> of conversion for 2 h). Only 2–3% of <sup>18</sup>O in the HCHO and H<sub>2</sub>O are remarkably low in spite of the use of 98% of <sup>18</sup>O<sub>2</sub>. These unexpectedly low values seem to be originated from the fast exchange of these products with surface –OH groups at around 873 K after formation. The <sup>18</sup>O% values of CO<sub>2</sub> range around 20–50%, which are higher values than those of HCHO and H<sub>2</sub>O. However, these values were lower than the 98% of reactant <sup>18</sup>O<sub>2</sub>. Similar results were reported by Koranne et al., over V oxide/SiO<sub>2</sub> [20]. Thus, it is difficult to know the source of oxygen in these products by the <sup>18</sup>O<sub>2</sub> tracer studies. However, it is clear that HCHO or CH<sub>3</sub>OH interacts rapidly with the surface of SiO<sub>2</sub>. The oxygen in CO<sub>2</sub> may come from anions of SiO<sub>2</sub>.

### 3.6. The oxidation of C<sub>2</sub>H<sub>6</sub> over silica

In order to know the dehydrogenation activity of silica, the oxidation of C<sub>2</sub>H<sub>6</sub> over various silicas was carried out in the presence and absence of oxygen. The results are shown in table 3. The selectivity to C<sub>2</sub>H<sub>4</sub> at 873 K is ca. 90%. Thus, the rate of C<sub>2</sub>H<sub>4</sub> formation indi-

cates the dehydrogenation activity of SiO<sub>2</sub>. The rates over ADM, OX50, and A300 run roughly parallel with the values of surface area in the absence of oxygen. In the presence of gaseous oxygen, the rates increase slightly for A300 and OX50 and ca. 6 times for ADM. There appears no big difference between oxidation reactions in the presence and absence of gaseous oxygen. These data suggest that the C<sub>2</sub>H<sub>4</sub> formation takes place via hydrogen abstraction from C<sub>2</sub>H<sub>6</sub> by lattice oxygen of SiO<sub>2</sub>. In the case of CH<sub>4</sub>, the activity of hydrogen abstraction was about 10 times smaller than that of C<sub>2</sub>H<sub>6</sub> on SiO<sub>2</sub> at 873 K. Kastanas et al. reported similar results with CH<sub>4</sub> and C<sub>2</sub>H<sub>6</sub> [21].

### 3.7. Summary and tentative mechanism

Our results can be summarized as follows: (1) The results over SiO<sub>2</sub> from metal Si are nearly the same as those over commercial SiO<sub>2</sub> in the partial oxidations of CH<sub>4</sub>. The rate of CH<sub>4</sub> partial oxidation does not depend on the SiO<sub>2</sub> area in the range 0.5–400 m<sup>2</sup> g<sup>-1</sup>. (2) The CH<sub>3</sub>OH formation was confirmed at very low conversion. (3) Gaseous oxygen is needed for the CH<sub>3</sub>OH and HCHO formation over SiO<sub>2</sub> and the rates depend on oxygen pressures. (4) The hydrogen abstraction from

Table 3

Dehydrogenation of C<sub>2</sub>H<sub>6</sub> over some silica in the presence and the absence of gaseous oxygen. Reaction time: 5 min, temperature = 873 K,  $p(\text{C}_2\text{H}_6) = 20$  Torr, catalyst: 0.3 g

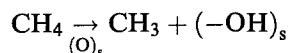
Silica <sup>a</sup>	Rate of C <sub>2</sub> H <sub>4</sub> formation (μmol g <sup>-1</sup> )	
	without O <sub>2</sub>	with 5% of O <sub>2</sub>
ADM	0.36	2.2
A300	1.0	1.3
OX50	0.55	0.75

<sup>a</sup> See table 2. This experiment was carried out using a closed circulation system without cooling at 77 K (fig. 1).

C<sub>2</sub>H<sub>6</sub> takes place on SiO<sub>2</sub> even in the absence of gaseous oxygen.

Sun et al. [14] have proposed that the HCHO formation did not originate from methyl and methoxy radicals but from methoxy surface complexes under the consideration of activation energy features. Parmaliana et al. [13] have proposed the reaction of surface species of CH<sub>4</sub> and oxygen.

In this work, however, both heterogeneous and homogeneous steps seem to be necessary in the case of CH<sub>3</sub>OH formation. The SiO<sub>2</sub> seems to play an important role on the hydrogen abstraction and CH<sub>3</sub> radical formation in the scheme



where (O)<sub>s</sub> is surface oxygen. A peroxy radical will be formed homogeneously, then methoxy radical will be formed:



The CH<sub>3</sub>OH and HCHO may be formed homogeneously or heterogeneously on the surface from methoxy radicals. If the steps of peroxy and methoxy radical formations are slow, the rate of CH<sub>3</sub>OH or HCHO formation will become slow and the effect of surface area size may disappear. If the reaction proceeds via surface methoxy species or adsorbed species [13,14], the rate should depend on the area of SiO<sub>2</sub> and, furthermore, CH<sub>3</sub>OH and HCHO will be produced by the lattice oxygen in the absence of gaseous oxygen. But our results are not in agreement with them. The main role of SiO<sub>2</sub> seem to be in the hydrogen abstraction from CH<sub>4</sub> and from CH<sub>3</sub>OH to HCHO without further oxidation in the case of partial oxidation.

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